

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/757,677 | Applicant(s)/Patent Under Reexamination FUJII ET AL. | |
| | Examiner Anthony H Nguyen | Art Unit 2854 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-5,552,859 | 09-1996 | Nakagawa et al. | 399/23 |
| | B | US-6,266,512 | 07-2001 | de Koning et al. | 399/370 |
| | C | US-6,091,927 | 07-2000 | Hattori et al. | 399/367 |
| | D | US-5,515,150 | 05-1996 | Yoshie et al. | 399/367 |
| | E | US-6,601,842 | 08-2003 | Kobayashi et al. | 271/3.14 |
| | F | US-5,443,252 | 08-1995 | Morinaga et al. | 271/127 |
| | G | US-5,132,741 | 07-1992 | Kitajima et al. | 399/370 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.